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Contents

NANOIMAGING INSTRUMENTS

- 11839 03
 Recent advances in nano-scale spatial resolution x-ray microscopy instrumentation at NSLS-II (Invited Paper) [11839-3]
- 11839 04 X-ray microscopy developments at Sirius-LNLS: first commissioning experiments at the Carnauba beamline [11839-6]
- 11839 05 **Design of the in situ nanoprobe beamline at the Advanced Photon Source** [11839-7]
- 11839 08 Visualization of shocked material instabilities using a fast-framing camera and XFEL four-pulse train [11839-14]

NANOIMAGING APPLICATIONS

- 11839 0C Color ptychography with a hyperspectral x-ray camera [11839-2]
- 11839 0D Soft x-ray linear dichroic ptychography: the study of crystal orientation in biominerals [11839-5]

NOVEL METHODS

- 11839 OF Ptychopy: GPU framework for ptychographic data analysis [11839-4]
- 11839 01 High-resolution phase-sensitive x-ray imaging technique based on the bilens system in an advanced optical layout [11839-13]